

## Features

- First-in First-out Dual Port Memory
- 16384 bits x 9 Organization
- Fast Flag and Access Times: 15, 30 ns
- Wide Temperature Range: - 55°C to + 125°C
- Fully Expandable by Word Width or Depth
- Asynchronous Read/Write Operations
- Empty, Full and Half Flags in Single Device Mode
- Retransmit Capability
- Bi-directional Applications
- Battery Back-up Operation: 2V Data Retention
- TTL Compatible
- Single 5V  $\pm$  10% Power Supply
- No Single Event Latch-up below a LET Threshold of 80 MeV/mg/cm<sup>2</sup>
- Tested up to a Total Dose of 30 krad (Si) according to MIL STD 883 Method 1019
- Quality grades: QML Q and V with SMD 5962-93177 and ESCC with specification 9301/048

## Description

The M67206H implements a first-in first-out algorithm, featuring asynchronous read/write operations. The FULL and EMPTY flags prevent data overflow and under-flow. The Expansion logic allows unlimited expansion in word size and depth with no timing penalties. Twin address pointers automatically generate internal read and write addresses, and no external address information is required. Address pointers are automatically incremented with the write pin and read pin. The 9 bits wide data are used in data communications applications where a parity bit for error checking is necessary. The Retransmit pin resets the Read pointer to zero without affecting the write pointer. This is very useful for retransmitting data when an error is detected in the system.

Using an array of eight transistors (8T) memory cell, the M67206H combines an extremely low standby supply current (typ = 0.1  $\mu$ A) with a fast access time at 15 ns over the full temperature range. All versions offer battery backup data retention capability with a typical power consumption at less than 2  $\mu$ W.

The M67206H is processed according to the methods of the latest revision of the MIL PRF 38535 (Q and V) or ESCC 9000.



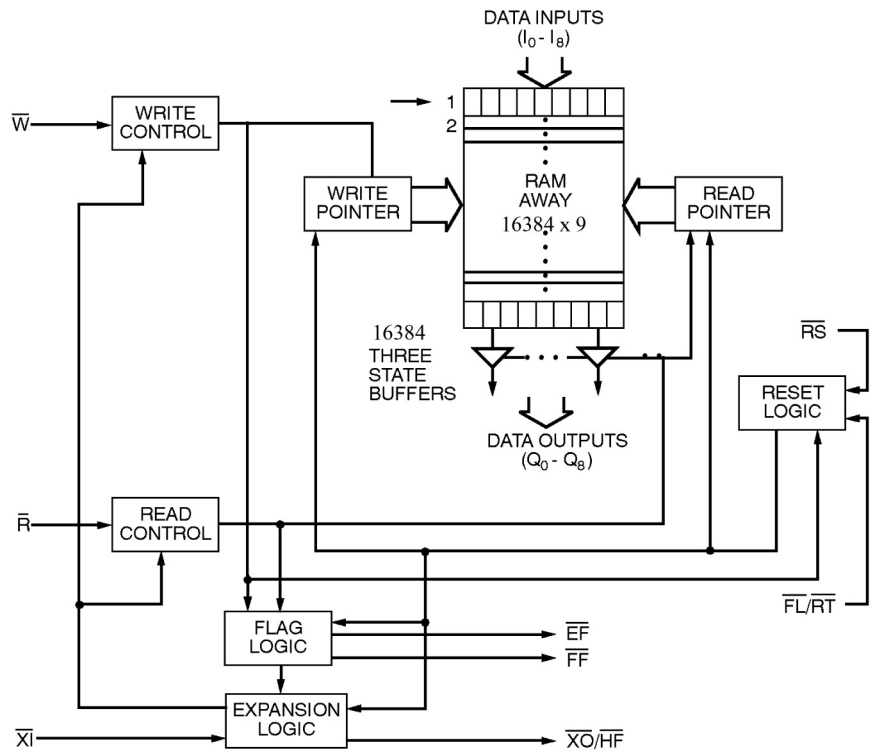
**Rad. Tolerant  
High Speed  
16 Kb x 9  
Parallel FIFO**

**M67206H**

Rev. 4143J-AERO-04/07

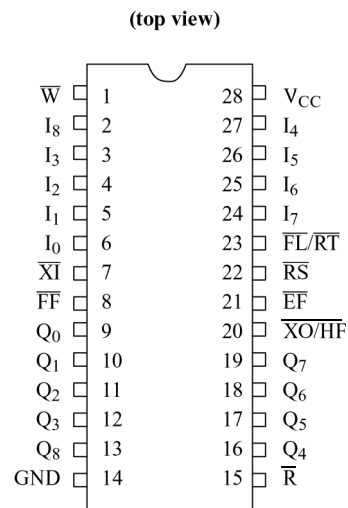


## Block Diagram



## Pin Configuration

DIL ceramic 28-pin 300 mils  
FP 28-pin 400 mils



## Pin Description

Names	Description
I0-8	Inputs
Q0-8	Outputs
W	Write Enable
R	Read Enable
RS	Reset
EF	Empty Flag
FF	Full Flag
XO/HF	Expansion Out/Half-Full Flag
XI	Expansion IN
FL/RT	First Load/Retransmit
VCC	Power Supply
GND	Ground

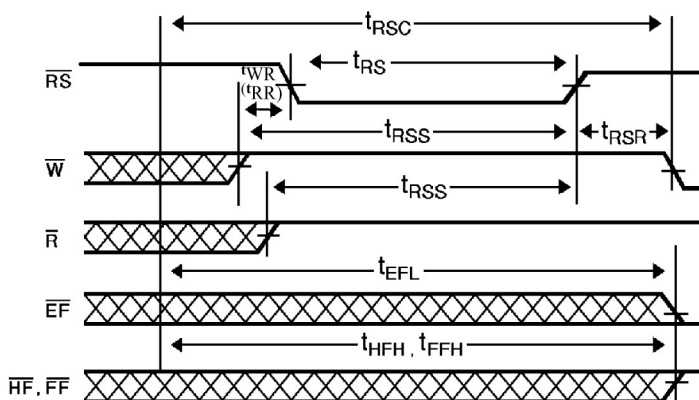
### Data In ( $I_0 - I_8$ )

Data inputs for 9-bit data

### Reset ( $\overline{RS}$ )

Reset occurs whenever the Reset ( $\overline{RS}$ ) input is taken to a low state. Reset returns both internal read and write pointers to the first location. A reset is required after power-up before a write operation can be enabled. Both the Read Enable ( $\overline{R}$ ) and Write Enable ( $\overline{W}$ ) inputs must be in the high state during the period shown in Figure 1 (i.e.  $t_{RSS}$  before the rising edge of  $\overline{RS}$ ) and should not change until  $t_{RSS}$  after the rising edge of  $\overline{RS}$ . The Half-Full Flag ( $\overline{HF}$ ) will be reset to high After Reset ( $\overline{RS}$ )

**Figure 1.** Reset



- Notes:
1.  $\overline{EF}$ ,  $\overline{FF}$  and  $\overline{HF}$  may change status during reset, but flags will be valid at  $t_{RSC}$ .
  2.  $\overline{W}$  and  $\overline{R}$  = VIH around the rising edge of  $\overline{RS}$ .

## Write Enable ( $\overline{W}$ )

A write cycle is initiated on the falling edge of this input if the Full Flag ( $\overline{FF}$ ) is not set. Data set-up and hold times must be maintained in the rise time of the leading edge of the Write Enable ( $\overline{W}$ ). Data is stored sequentially in the Ram array, regardless of any current read operation.

Once half the memory is filled, and during the falling edge of the next write operation, the Half-Full Flag ( $\overline{HF}$ ) will be set to low and remain in this state until the difference between the write and read pointers is less than or equal to half of the total available memory in the device. The Half-Full Flag ( $\overline{HF}$ ) is then reset by the rising edge of the read operation.

To prevent data overflow, the Full Flag ( $\overline{FF}$ ) will go low, inhibiting further write operations. On completion of a valid read operation, the Full Flag ( $\overline{FF}$ ) will go high after TRFF, allowing a valid  $\overline{W}$  write to begin. When the FIFO stack is full, the internal write pointer is blocked from  $\overline{W}$ , so that external changes to  $\overline{W}$  will have no effect on the full FIFO stack.

## Read Enable ( $\overline{R}$ )

A read cycle is initiated on the falling edge of the Read Enable ( $\overline{R}$ ) provided that the Empty Flag ( $\overline{EF}$ ) is not set. The data is accessed on a first-in/first-out basis, not including any current write operations. After Read Enable ( $\overline{R}$ ) goes high, the Data Outputs (Q0 - Q8) will return to a high impedance state until the next Read operation. When all the data in the FIFO stack has been read, the Empty Flag ( $\overline{EF}$ ) will go low, allowing the "final" read cycle, but inhibiting further read operations while the data outputs remain in a high impedance state. Once a valid write operation has been completed, the Empty Flag ( $\overline{EF}$ ) will go high after tWEF and a valid read may then be initiated. When the FIFO stack is empty, the internal read pointer is blocked from  $\overline{R}$ , so that external changes to  $\overline{R}$  will have no effect on the empty FIFO stack.

## First Load/Retransmit (FL/RT)

This pin is a dual-purpose input. In the Depth Expansion Mode, this pin is connected to ground to indicate that it is the first loaded (see Operating Modes). In the Single Device Mode, this pin acts as the retransmit input. The Single Device Mode is initiated by connecting the Expansion In ( $\overline{XI}$ ) to ground.

The M67206H can be set to retransmit data when the Retransmit Enable Control ( $\overline{RT}$ ) input is pulsed low. A retransmit operation will set the internal read point to the first location and will not affect the write pointer. Read Enable ( $\overline{R}$ ) and Write Enable ( $\overline{W}$ ) must be in the high state during retransmit. The retransmit feature is intended for use when a number of writes are equal to or less than the depth of the FIFO has occurred since the last RS cycle. The retransmit feature is not compatible with the Depth Expansion Mode and will affect the Half-Full Flag ( $\overline{HF}$ ), in accordance with the relative locations of the read and write pointers.

## Expansion In ( $\overline{XI}$ )

The  $\overline{XI}$  input is a dual-purpose pin. Expansion In ( $\overline{XI}$ ) is connected to GND to indicate an operation in the single device mode. Expansion In ( $\overline{XI}$ ) is connected to Expansion Out ( $\overline{XO}$ ) of the previous device in the Depth Expansion or Daisy Chain modes.

## Full Flag ( $\overline{FF}$ )

The Full Flag ( $\overline{FF}$ ) will go low, inhibiting further write operations when the write pointer is one location less than the read pointer, indicating that the device is full. If the read pointer is not moved after Reset ( $\overline{RS}$ ), the Full Flag ( $\overline{FF}$ ) will go low after 16384 writes.

## Empty Flag ( $\overline{EF}$ )

The Empty Flag ( $\overline{EF}$ ) will go low, inhibiting further read operations when the read pointer is equal to the write pointer, indicating that the device is empty.

**Expansion Out/Half-Full Flag ( $\overline{XO}/\overline{HF}$ )**

The  $\overline{XO}/\overline{HF}$  pin is a dual-purpose output. In the single device mode, when Expansion In ( $\overline{XI}$ ) is connected to ground, this output acts as an indication of a half-full memory.

After half the memory is filled and on the falling edge of the next write operation, the Half-Full Flag ( $\overline{HF}$ ) will be set to low and will remain set until the difference between the write and read pointers is less than or equal to half of the total memory of the device. The Half-Full Flag ( $\overline{HF}$ ) is then reset by the rising edge of the read operation.

In the Depth Expansion Mode, Expansion In ( $\overline{XI}$ ) is connected to Expansion Out ( $\overline{XO}$ ) of the previous device. This output acts as a signal to the next device in the Daisy Chain by providing a pulse to the next device when the previous device reaches the last memory location.

**Data Output ( $Q_0 - Q_8$ )**

DATA output for 9-bit wide data. This data is in a high impedance condition whenever Read ( $\overline{R}$ ) is in a high state.



**Table 1.** Reset and Retransmit  
Single Device Configuration/Width Expansion Mode

Mode	Inputs			Internal Status		Outputs		
	$\overline{RS}$	$\overline{RT}$	$\overline{XI}$	Read Pointer	Write Pointer	$\overline{EF}$	$\overline{FF}$	$\overline{HF}$
Reset	0	X	0	Location Zero	Location Zero	0	1	1
Retransmit	1	0	0	Location Zero	Unchanged	X	X	X
Read/Write	1	1	0	Increment <sup>(1)</sup>	Increment <sup>(1)</sup>	X	X	X

Note: 1. Pointer will increment if flag is high.

**Table 2.** Reset and First Load Truth Table  
Depth Expansion/Compound Expansion Mode

Mode	Inputs			Internal Status		Outputs	
	$\overline{RS}$	$\overline{FL}$	$\overline{XI}$	Read Pointer	Write Pointer	$\overline{EF}$	$\overline{FF}$
Reset First Device	0	0	(1)	Location Zero	Location Zero	0	1
Reset All Other Devices	0	1	(1)	Location Zero	Location Zero	0	1
Read/Write	1	X	(1)	X	X	X	X

Note: 1.  $\overline{XI}$  is connected to  $\overline{XO}$  of previous device.  
See Figure 4.

## Depth Expansion (Daisy Chain) Mode

The M67206H can be easily adapted for applications which require more than 16384 words. Figure 4 demonstrates Depth Expansion using three M67206Hs. Any depth can be achieved by adding an additional M67206H.

The M67206H operates in the Depth Expansion configuration if the following conditions are met:

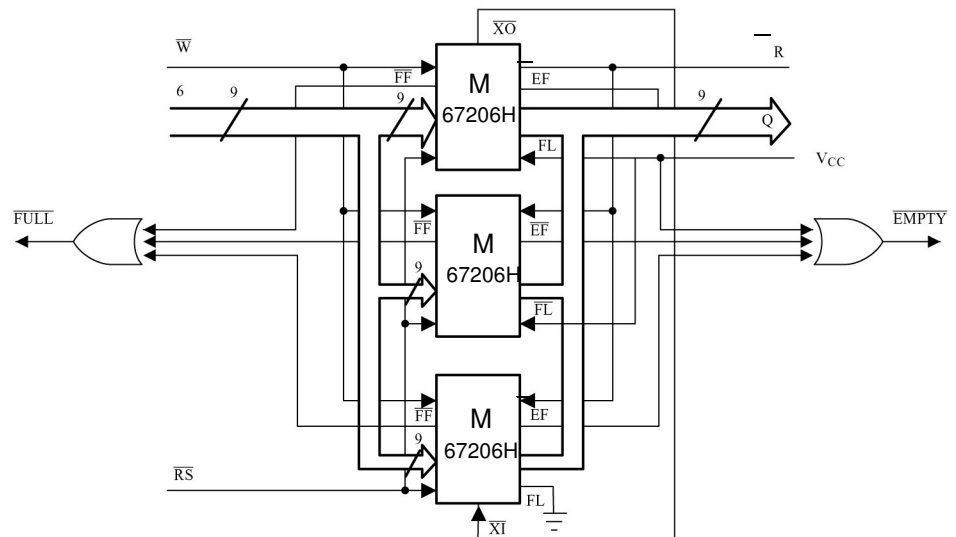
1. The first device must be designated by connecting the First Load ( $\overline{FL}$ ) control input to ground.
2. All other devices must have  $\overline{FL}$  in the high state.
3. The Expansion Out ( $\overline{XO}$ ) pin of each device must be connected to the Expansion In ( $\overline{XI}$ ) pin of the next device. See Figure 4
4. External logic is needed to generate a composite Full Flag ( $\overline{FF}$ ) and Empty Flag ( $\overline{EF}$ ). This requires that all  $\overline{EF}$ 's and all  $\overline{FF}$ 's be ORed (i.e. all must be set to generate the correct composite  $\overline{FF}$  or  $\overline{EF}$ ). See Figure 4.
5. The Retransmit ( $\overline{RT}$ ) function and Half-Full Flag ( $\overline{HF}$ ) are not available in the Depth Expansion Mode.

## Compound Expansion Module

It is quite simple to apply the two expansion techniques described above together to create large FIFO arrays (see Figure 5).

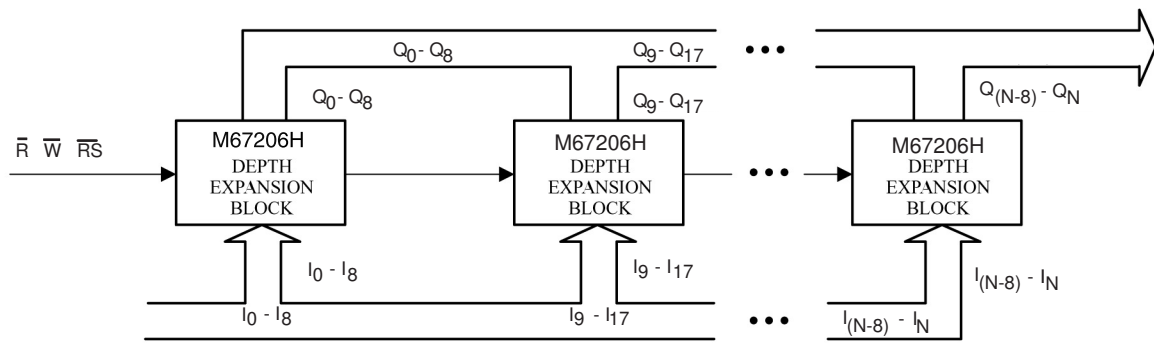
## Data Flow – Through Modes

In the write flow-through mode (Figure 18), the FIFO stack allows a single word of data to be written immediately after a single word of data has been read from a full FIFO stack. The  $\overline{R}$  line causes the  $\overline{FF}$  to be reset, but the  $\overline{W}$  line, being low, causes it to be set again in anticipation of a new data word. The new word is loaded into the FIFO stack on the leading edge of  $\overline{W}$ . The  $\overline{W}$  line must be toggled when  $\overline{FF}$  is not set in order to write new data into the FIFO stack and to increment the write pointer.



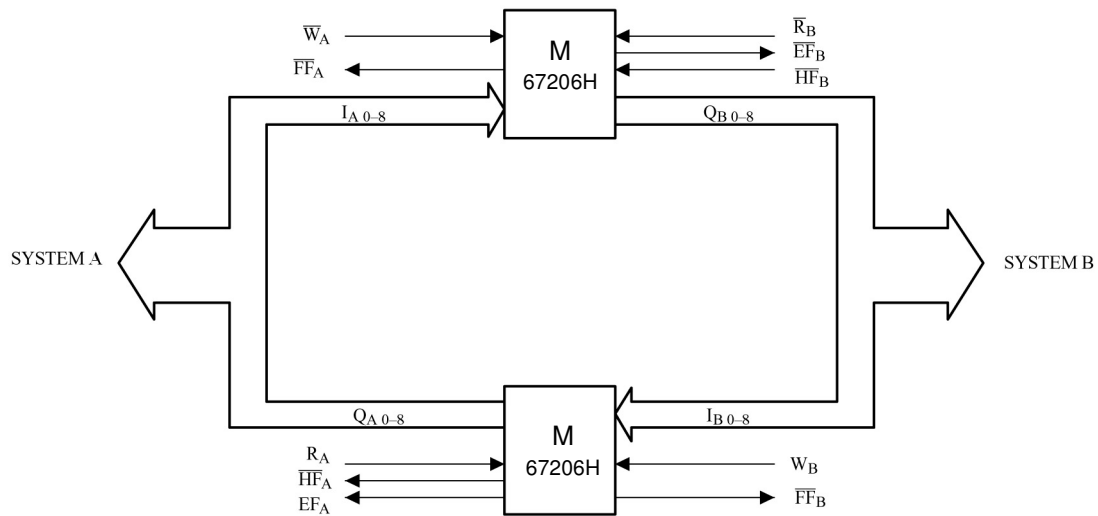


**Figure 5. Compound FIFO Expansion**



- Notes:
1. For depth expansion block see section on Depth Expansion and Figure 4.
  2. For Flag detection see section on Width Expansion and Figure 3.

**Figure 6. Bi-directional FIFO Mode**



## Electrical Characteristics

### Absolute Maximum Ratings

Supply voltage (VCC - GND):..... - 0.5V to 7.0V

Input or Output voltage applied: (GND - 0.3V) to (Vcc + 0.3V)

Storage temperature:..... - 65 °C to + 150 °C

**\*NOTICE:** Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

### DC Parameters

DC Test Conditions

TA = -55°C to + 125°C; Vss = 0V; Vcc = 4.5V to 5.5V

Parameter	Description	M67206H-30	M67206H-15	Unit	Value
I <sub>CCOP</sub> <sup>(1)</sup>	Operating supply current	110	120	mA	Max
I <sub>CCSB</sub> <sup>(2)</sup>	Standby supply current	5	5	mA	Max
I <sub>CCPD</sub> <sup>(3)</sup>	Power down current	400	400	μA	Max

- I<sub>CC</sub> measurements are made with outputs open.
- $\bar{R} = \bar{W} = \bar{RS} = \bar{FL/RT} = V_{IH}$ .
- All input = Vcc.

Parameter	Description	M67206H	Unit	Value
ILI <sup>(1)</sup>	Input leakage current	± 1	μA	Max
ILO <sup>(2)</sup>	Output leakage current	± 1	μA	Max
VIL <sup>(3)</sup>	Input low voltage	0.8	V	Max
VIH <sup>(3)</sup>	Input high voltage	2.2	V	Min
VOL <sup>(4)</sup>	Output low voltage	0.4	V	Max
VOH <sup>(4)</sup>	Output high voltage	2.4	V	Min
C IN <sup>(5)</sup>	Input capacitance	8	pF	Max
C OUT <sup>(5)</sup>	Output capacitance	8	pF	Max

- $0.4 \leq V_{in} \leq V_{cc}$ .
- $\bar{R} = V_{IH}$ ,  $0.4 \leq V_{OUT} \leq V_{CC}$ .
- $V_{IH} \text{ max} = V_{cc} + 0.3 \text{ V}$ .  $V_{IL} \text{ min} = -0.3\text{V}$  or  $-1\text{V}$  pulse width 50 ns. For XI input,  $V_{IH} = 2.8\text{V}$
- Vcc min, IOL = 8 mA, IOH = -2 mA.
- Guaranteed but not tested.

## AC Test Conditions

Input pulse levels: Gnd to 3.0V

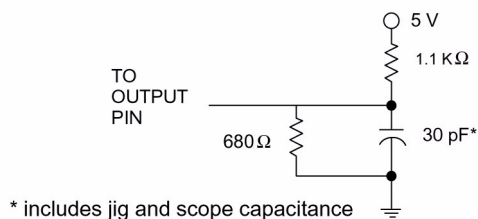
Input rise/Fall times: 5 ns

Input timing reference levels: 1.5V

Output reference levels: 1.5V

Output load: See Figure 7

**Figure 7.** Output Load



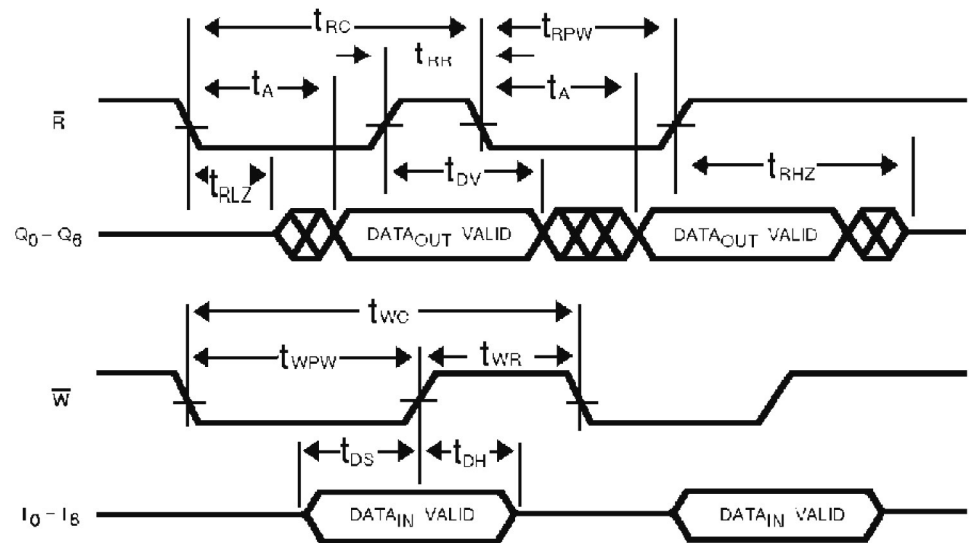
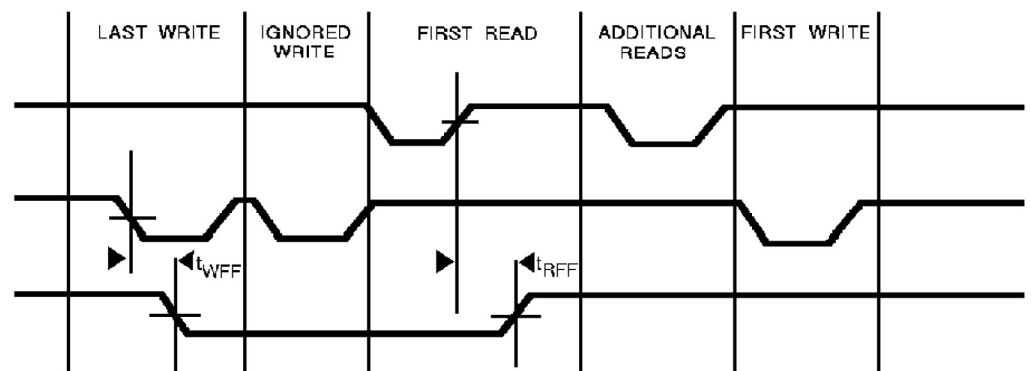
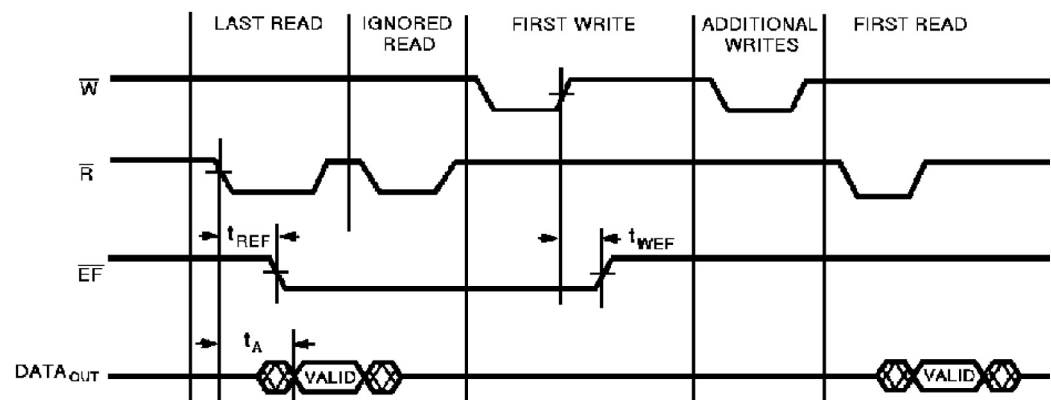
**Table 3.** AC Test Conditions

Symbol <sup>(1)</sup>	Symbol <sup>(2)</sup>	Parameter <sup>(3) (4)</sup>	M67206H- 15		M67206H- 30		Unit
			Min	Max	Min	Max	
Read Cycle							
TRLRL	tRC	Read cycle time	25	–	40	–	ns
TRLQV	tA	Access time	–	15	–	30	ns
TRHRL	tRR	Read recovery time	10	–	10	–	ns
TRLRH	tRPW	Read pulse width <sup>(5)</sup>	15	–	30	–	ns
TRLQX	tRLZ	Read low to data low Z <sup>(6)</sup>	0	–	0	–	ns
TWHQX	tWLZ	Write low to data low Z <sup>(6) (7)</sup>	3	–	5	–	ns
TRHQX	tDV	Data valid from read high	5	–	5	–	ns
TRHQZ	tRHZ	Read high to data high Z <sup>(6)</sup>	–	15	–	20	ns
Write Cycle							
TWLWL	tWC	Write cycle time	25	–	40	–	ns
TWLWH	tWPW	Write pulse width <sup>(5)</sup>	15	–	30	–	ns
TWHWL	tWR	Write recovery time	10	–	10	–	ns
TDVWH	tDS	Data set-up time	9	–	18	–	ns
TWHDX	tDH	Data hold time	0	–	0	–	ns
Reset Cycle							
TRSLWL	tRSC	Reset cycle time	25	–	40	–	ns
TRSLRSH	tRS	Reset pulse width <sup>(5)</sup>	15	–	30	–	ns

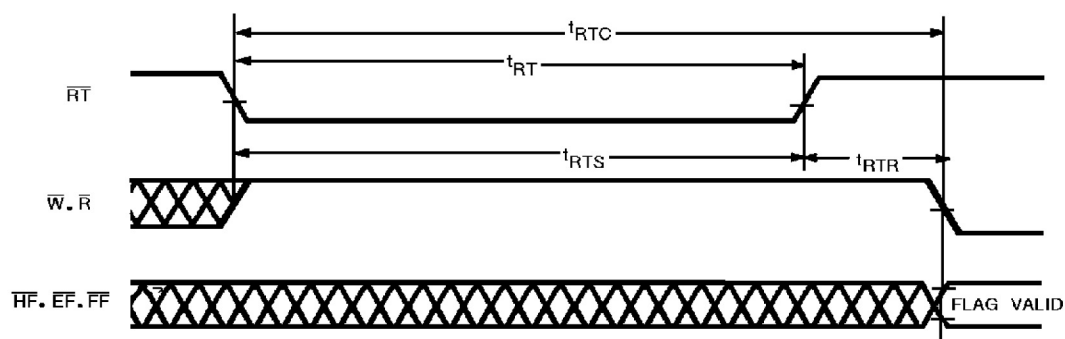
**Table 3. AC Test Conditions (Continued)**

Symbol <sup>(1)</sup>	Symbol <sup>(2)</sup>	Parameter <sup>(3) (4)</sup>	M67206H- 15		M67206H- 30		Unit
			Min	Max	Min	Max	
TWHRSH	tRSS	Reset set-up time	20	–	30	–	ns
TRSHWL	tRSR	Reset recovery time	10	–	10	–	ns
Retransmit Cycle							
TRTLWL	tRTC	Retransmit cycle time	25	–	40	–	ns
TRTLRTH	tRT	Retransmit pulse width <sup>(5)</sup>	15	–	30	–	ns
TWHRTH	tRTS	Retransmit set-up time <sup>(6)</sup>	15	–	30	–	ns
TRTHWL	tRTR	Retransmit recovery time	10	–	10	–	ns
Flags							
TRSLEFL	tEFL	Reset to EF low	–	25	–	30	ns
TRSLFFH	tHFH, tFFH	Reset to HF/FF high	–	25	–	30	ns
TRLEFL	tREF	Read low to EF low	–	25	–	30	ns
TRHFFH	tRFF	Read high to FF high	–	25	–	30	ns
TEFHRH	tRPE	Read width after EF high	15	–	30	–	ns
TWHEFH	tWEF	Write high to EF high	–	15	–	30	ns
TWLFFL	tWFF	Write low to FF low	–	20	–	30	ns
TWLHFL	tWHF	Write low to HF low	–	30	–	30	ns
TRHHFH	tRHF	Read high to HF high	–	30	–	30	ns
TFHWH	tWPF	Write width after FF high	15	–	30	–	ns
Expansion							
TWLXOL	tXOL	Read/Write to XO low	–	15	–	30	ns
TWHXOH	tXOH	Read/Write to XO high	–	15	–	30	ns
TXILXIH	tXI	XI pulse width	15	–	30	–	ns
TXIHXL	tXIR	XI recovery time	10	–	10	–	ns
TXILRL	tXIS	XI set-up time	10	–	10	–	ns

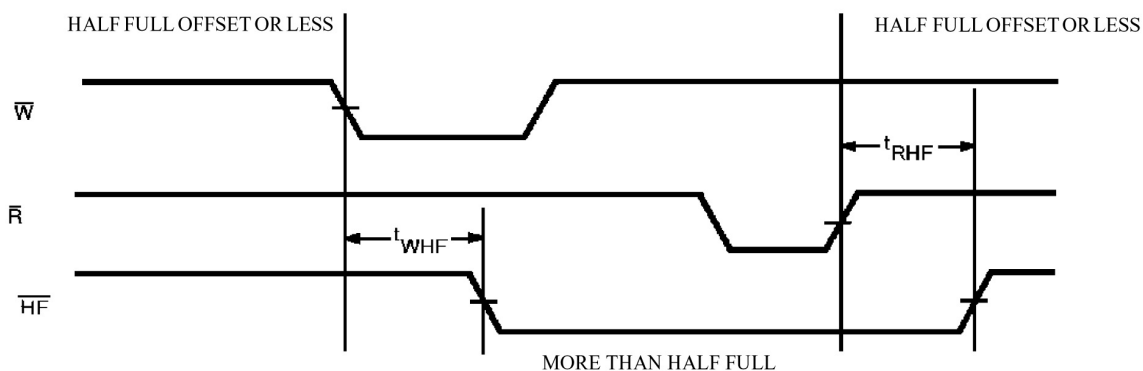
1. STD symbol.
2. ALT symbol.
3. Timings referenced as in AC test conditions.
4. All parameters tested only.
5. Pulse widths less than minimum value are not allowed.
6. Values guaranteed by design, not currently tested.
7. Only applies to read data flow-through mode.

**Figure 8.** Asynchronous Write and Read Operation**Figure 9.** Full Flag from Last Write to First Read**Figure 10.** Empty Flag from Last Read to First Write

**Figure 11. Retransmit**



**Figure 12. Empty Flag Timing**



**Figure 13. Full Flag Timing**

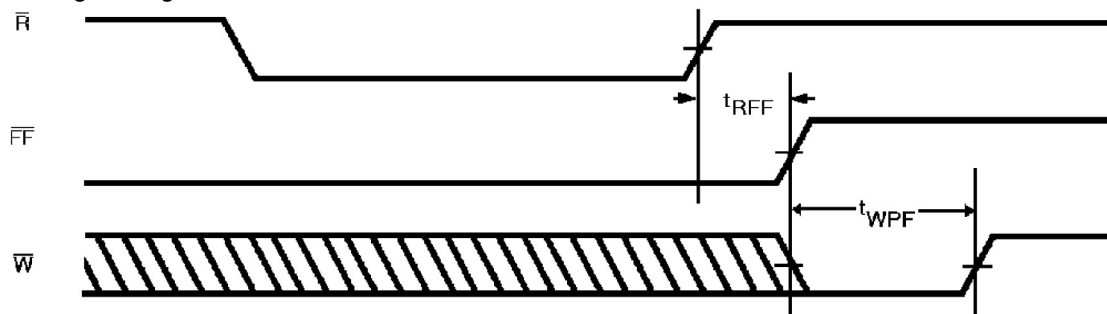


Figure 14. Half Full Flag Timing

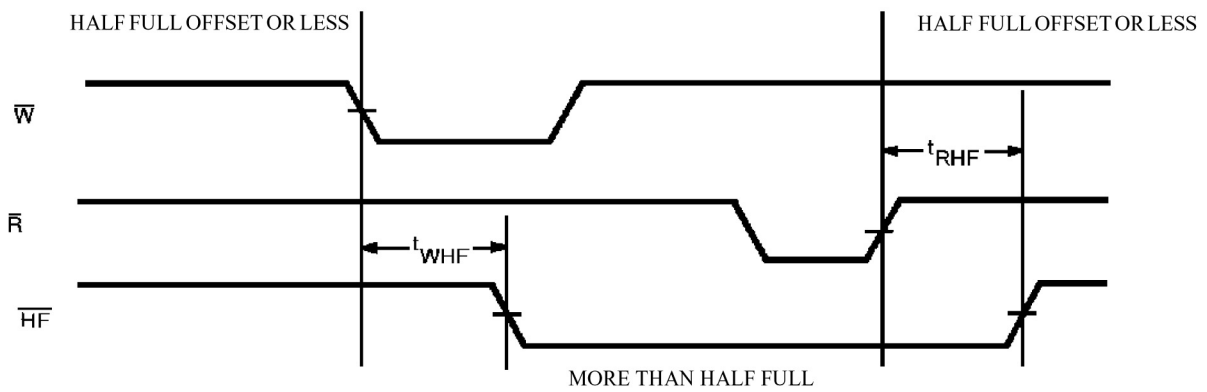


Figure 15. Expansion Out

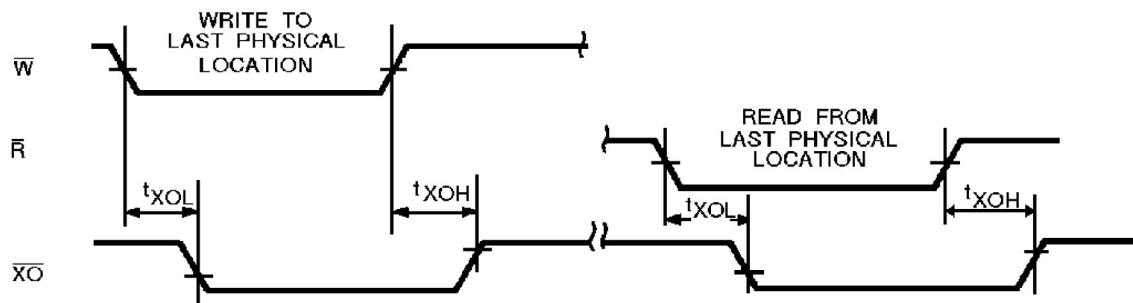
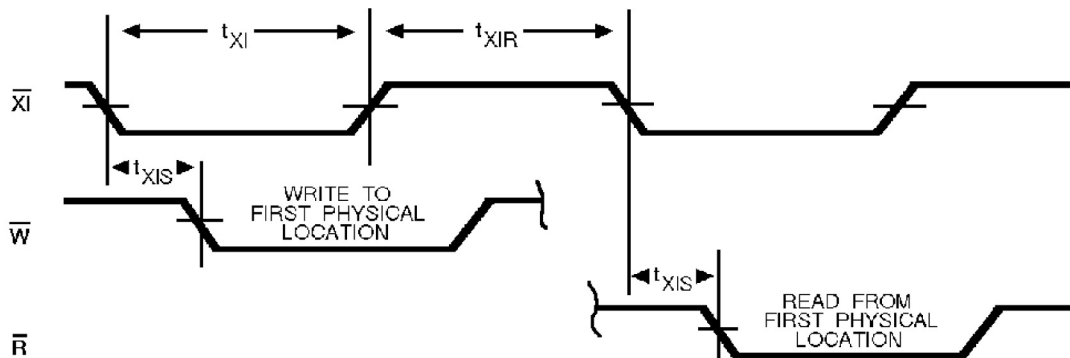
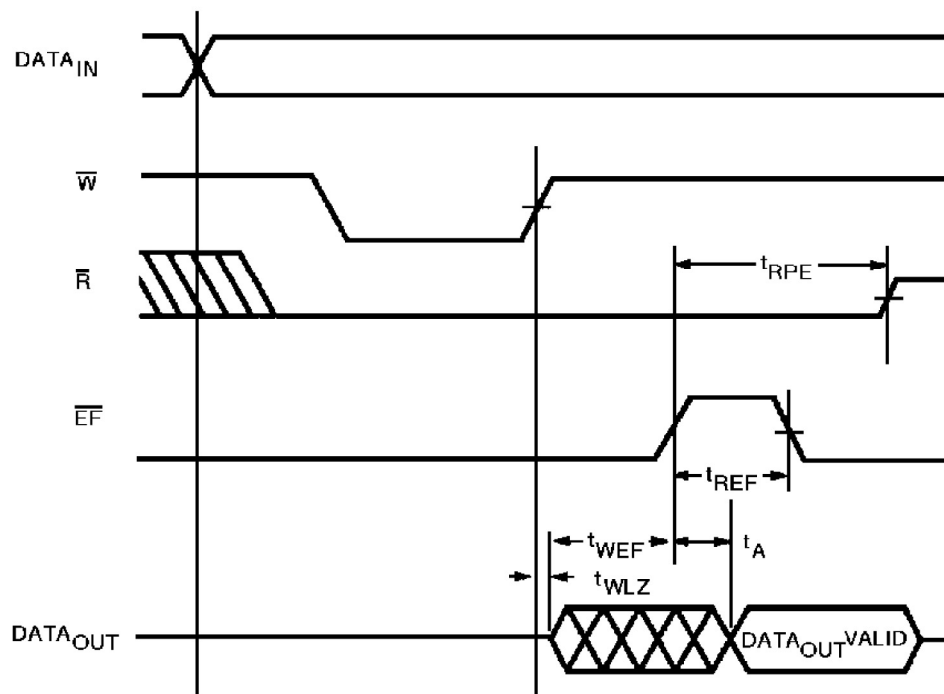


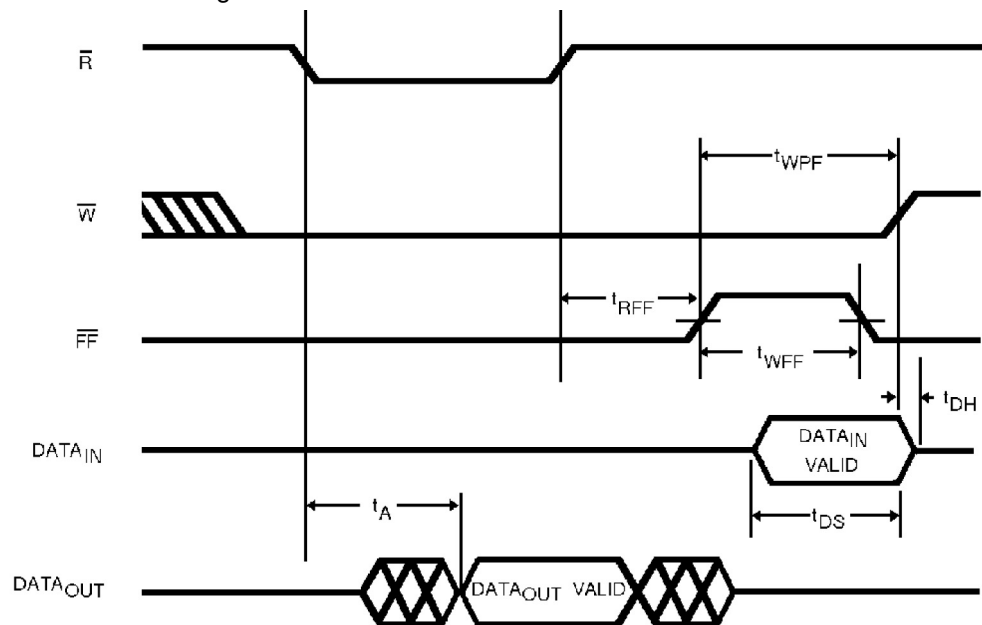
Figure 16. Expansion In



**Figure 17. Read Data Flow – Through Mode**



**Figure 18. Write Data Flow – Through Mode**





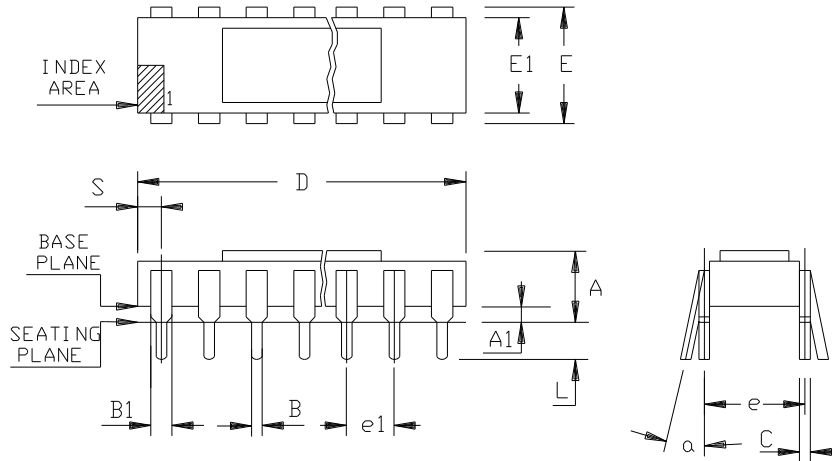
## Ordering Information

Part Number	Temperature Range	Speed	Package	Quality Flow
MMCP-67206HV-15-E <sup>(1)</sup>	25°C	15 ns	SB28.3	Engineering Samples
SMCP-67206HV-15SCC	-55 to +125°C	15 ns	SB28.3	ESCC
SMCP-67206HV-30SCC	-55 to +125°C	30 ns	SB28.3	ESCC
5962-9317708QTC	-55 to +125°C	15 ns	SB28.3	QML Q
5962-9317707QTC	-55 to +125°C	30 ns	SB28.3	QML Q
5962-9317708VTC	-55 to +125°C	15 ns	SB28.3	QML V
5962D9317708VTC	-55 to +125°C	15 ns	SB28.3	QML V RHA
5962D9317707VTC	-55 to +125°C	30 ns	SB28.3	QML V RHA
5962-9317707VTC	-55 to +125°C	30 ns	SB28.3	QML V
MMDP-67206HV-15-E	25°C	15 ns	FP28.4	Engineering Samples
SMDP-67206HV-15SCC	-55 to +125°C	15 ns	FP28.4	ESCC
SMDP-67206HV-30SCC	-55 to +125°C	30 ns	FP28.4	ESCC
5962-9317708QNC	-55 to +125°C	15 ns	FP28.4	QML Q
5962-9317707QNC	-55 to +125°C	30 ns	FP28.4	QML Q
5962-9317708VNC	-55 to +125°C	15 ns	FP28.4	QML V
5962-9317707VNC	-55 to +125°C	30 ns	FP28.4	QML V
5962D9317708VNC	-55 to +125°C	15 ns	FP28.4	QML V RHA
5962D9317707VNC	-55 to +125°C	30 ns	FP28.4	QML V RHA
MM0 -67206HV-15SV <sup>(1)</sup>	-55 to +125°C	15 ns	Die	QML V
MM067206HV-15-E <sup>(1)</sup>	25°C	15 ns	Die	Engineering Samples

Note: 1. Contact Atmel for availability.

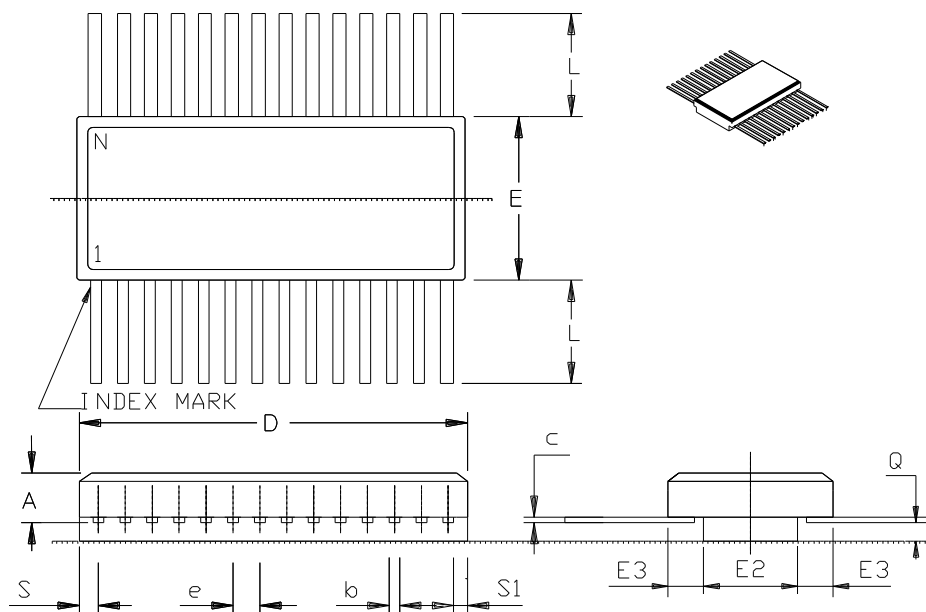
## Package Drawings

### 28-lead Side Braze (300 Mils)



	MM		INCH	
A	2.82	3.94	.111	.155
A1	0.63	1.14	.025	.045
B	0.38	0.53	.015	.021
B1	0.96	1.52	.038	.060
C	0.20	0.30	.008	.012
D	27.43	28.45	1.080	1.120
E	7.49	8.25	.295	.325
E1	7.11	7.87	.280	.310
L	3.18	4.44	.125	.175
S	1.10	2.03	.043	.080
e	7.62	TYP	.300	TYP
e1	2.54	TYP	.100	TYP
α	0°		15°	

## 28-lead Flat Pack (400 Mils)



	MM		INCH	
	Min	Max	Min	Max
A	2.29	3.30	.090	.130
b	0.38	0.48	.015	.019
c	0.08	0.15	.003	.006
D	---	18.80	---	.740
E	9.65	10.67	.380	.420
E2	4.57	---	.180	---
E3	0.76	---	.030	---
e	1.27	BSC	.050	BSC
L	6.35	9.40	.250	.370
Q	0.66	---	.026	---
S	---	1.30	---	.051
S1	0.00	---	.000	---
N	28		28	



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